# E. Lattice Semiconductor Corporation - <u>LFE3-70EA-6LFN484I Datasheet</u>



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#### Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

#### **Applications of Embedded - FPGAs**

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

#### Details

Product Status	Active
Number of LABs/CLBs	8375
Number of Logic Elements/Cells	67000
Total RAM Bits	4526080
Number of I/O	295
Number of Gates	-
Voltage - Supply	1.14V ~ 1.26V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	484-BBGA
Supplier Device Package	484-FPBGA (23x23)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/lfe3-70ea-6lfn484i

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# Introduction

The LatticeECP3<sup>™</sup> (EConomy Plus Third generation) family of FPGA devices is optimized to deliver high performance features such as an enhanced DSP architecture, high speed SERDES and high speed source synchronous interfaces in an economical FPGA fabric. This combination is achieved through advances in device architecture and the use of 65 nm technology making the devices suitable for high-volume, high-speed, low-cost applications.

The LatticeECP3 device family expands look-up-table (LUT) capacity to 149K logic elements and supports up to 586 user I/Os. The LatticeECP3 device family also offers up to 320 18 x 18 multipliers and a wide range of parallel I/O standards.

The LatticeECP3 FPGA fabric is optimized with high performance and low cost in mind. The LatticeECP3 devices utilize reconfigurable SRAM logic technology and provide popular building blocks such as LUT-based logic, distributed and embedded memory, Phase Locked Loops (PLLs), Delay Locked Loops (DLLs), pre-engineered source synchronous I/O support, enhanced sysDSP slices and advanced configuration support, including encryption and dual-boot capabilities.

The pre-engineered source synchronous logic implemented in the LatticeECP3 device family supports a broad range of interface standards, including DDR3, XGMII and 7:1 LVDS.

The LatticeECP3 device family also features high speed SERDES with dedicated PCS functions. High jitter tolerance and low transmit jitter allow the SERDES plus PCS blocks to be configured to support an array of popular data protocols including PCI Express, SMPTE, Ethernet (XAUI, GbE, and SGMII) and CPRI. Transmit Pre-emphasis and Receive Equalization settings make the SERDES suitable for transmission and reception over various forms of media.

The LatticeECP3 devices also provide flexible, reliable and secure configuration options, such as dual-boot capability, bit-stream encryption, and TransFR field upgrade features.

The Lattice Diamond<sup>™</sup> and ispLEVER<sup>®</sup> design software allows large complex designs to be efficiently implemented using the LatticeECP3 FPGA family. Synthesis library support for LatticeECP3 is available for popular logic synthesis tools. Diamond and ispLEVER tools use the synthesis tool output along with the constraints from its floor planning tools to place and route the design in the LatticeECP3 device. The tools extract the timing from the routing and back-annotate it into the design for timing verification.

Lattice provides many pre-engineered IP (Intellectual Property) modules for the LatticeECP3 family. By using these configurable soft core IPs as standardized blocks, designers are free to concentrate on the unique aspects of their design, increasing their productivity.



### Figure 2-2. PFU Diagram



### Slice

Slice 0 through Slice 2 contain two LUT4s feeding two registers, whereas Slice 3 contains two LUT4s only. For PFUs, Slice 0 through Slice 2 can be configured as distributed memory, a capability not available in the PFF. Table 2-1 shows the capability of the slices in both PFF and PFU blocks along with the operation modes they enable. In addition, each PFU contains logic that allows the LUTs to be combined to perform functions such as LUT5, LUT6, LUT7 and LUT8. There is control logic to perform set/reset functions (programmable as synchronous/ asynchronous), clock select, chip-select and wider RAM/ROM functions.

Table 2-1.	Resources ar	nd Modes	Available	per Slice
	11000 di 000 di		/ 11 aa	

	PFU E	BLock	PFF Block		
Slice	Resources Modes		Resources	Modes	
Slice 0	2 LUT4s and 2 Registers	Logic, Ripple, RAM, ROM	2 LUT4s and 2 Registers	Logic, Ripple, ROM	
Slice 1	2 LUT4s and 2 Registers	Logic, Ripple, RAM, ROM	2 LUT4s and 2 Registers	Logic, Ripple, ROM	
Slice 2	2 LUT4s and 2 Registers	Logic, Ripple, RAM, ROM	2 LUT4s and 2 Registers	Logic, Ripple, ROM	
Slice 3	2 LUT4s	Logic, ROM	2 LUT4s	Logic, ROM	

Figure 2-3 shows an overview of the internal logic of the slice. The registers in the slice can be configured for positive/negative and edge triggered or level sensitive clocks.

Slices 0, 1 and 2 have 14 input signals: 13 signals from routing and one from the carry-chain (from the adjacent slice or PFU). There are seven outputs: six to routing and one to carry-chain (to the adjacent PFU). Slice 3 has 10 input signals from routing and four signals to routing. Table 2-2 lists the signals associated with Slice 0 to Slice 2.



## Modes of Operation

Each slice has up to four potential modes of operation: Logic, Ripple, RAM and ROM.

### Logic Mode

In this mode, the LUTs in each slice are configured as 4-input combinatorial lookup tables. A LUT4 can have 16 possible input combinations. Any four input logic functions can be generated by programming this lookup table. Since there are two LUT4s per slice, a LUT5 can be constructed within one slice. Larger look-up tables such as LUT6, LUT7 and LUT8 can be constructed by concatenating other slices. Note LUT8 requires more than four slices.

### **Ripple Mode**

Ripple mode supports the efficient implementation of small arithmetic functions. In ripple mode, the following functions can be implemented by each slice:

- Addition 2-bit
- Subtraction 2-bit
- Add/Subtract 2-bit using dynamic control
- Up counter 2-bit
- Down counter 2-bit
- Up/Down counter with asynchronous clear
- Up/Down counter with preload (sync)
- Ripple mode multiplier building block
- Multiplier support
- Comparator functions of A and B inputs
  - A greater-than-or-equal-to B
  - A not-equal-to B
  - A less-than-or-equal-to B

Ripple Mode includes an optional configuration that performs arithmetic using fast carry chain methods. In this configuration (also referred to as CCU2 mode) two additional signals, Carry Generate and Carry Propagate, are generated on a per slice basis to allow fast arithmetic functions to be constructed by concatenating Slices.

### RAM Mode

In this mode, a 16x4-bit distributed single port RAM (SPR) can be constructed using each LUT block in Slice 0 and Slice 1 as a 16x1-bit memory. Slice 2 is used to provide memory address and control signals. A 16x2-bit pseudo dual port RAM (PDPR) memory is created by using one Slice as the read-write port and the other companion slice as the read-only port.

LatticeECP3 devices support distributed memory initialization.

The Lattice design tools support the creation of a variety of different size memories. Where appropriate, the software will construct these using distributed memory primitives that represent the capabilities of the PFU. Table 2-3 shows the number of slices required to implement different distributed RAM primitives. For more information about using RAM in LatticeECP3 devices, please see TN1179, LatticeECP3 Memory Usage Guide.

#### Table 2-3. Number of Slices Required to Implement Distributed RAM

	SPR 16X4	PDPR 16X4
Number of slices	3	3

Note: SPR = Single Port RAM, PDPR = Pseudo Dual Port RAM



Figure 2-4. General Purpose PLL Diagram



Table 2-4 provides a description of the signals in the PLL blocks.

Table 2-4. PLL Blocks Signal Descriptions

Signal	I/O	Description
CLKI	I	Clock input from external pin or routing
CLKFB	I	PLL feedback input from CLKOP, CLKOS, or from a user clock (pin or logic)
RST	I	"1" to reset PLL counters, VCO, charge pumps and M-dividers
RSTK	I	"1" to reset K-divider
WRDEL	I	DPA Fine Delay Adjust input
CLKOS	0	PLL output to clock tree (phase shifted/duty cycle changed)
CLKOP	0	PLL output to clock tree (no phase shift)
CLKOK	0	PLL output to clock tree through secondary clock divider
CLKOK2	0	PLL output to clock tree (CLKOP divided by 3)
LOCK	0	"1" indicates PLL LOCK to CLKI
FDA [3:0]	I	Dynamic fine delay adjustment on CLKOS output
DRPAI[3:0]	I	Dynamic coarse phase shift, rising edge setting
DFPAI[3:0]	I	Dynamic coarse phase shift, falling edge setting

# Delay Locked Loops (DLL)

In addition to PLLs, the LatticeECP3 family of devices has two DLLs per device.

CLKI is the input frequency (generated either from the pin or routing) for the DLL. CLKI feeds into the output muxes block to bypass the DLL, directly to the DELAY CHAIN block and (directly or through divider circuit) to the reference input of the Phase Detector (PD) input mux. The reference signal for the PD can also be generated from the Delay Chain signals. The feedback input to the PD is generated from the CLKFB pin or from a tapped signal from the Delay chain.

The PD produces a binary number proportional to the phase and frequency difference between the reference and feedback signals. Based on these inputs, the ALU determines the correct digital control codes to send to the delay



Input signals are fed from the sysl/O buffer to the input register block (as signal DI). If desired, the input signal can bypass the register and delay elements and be used directly as a combinatorial signal (INDD), a clock (INCK) and, in selected blocks, the input to the DQS delay block. If an input delay is desired, designers can select either a fixed delay or a dynamic delay DEL[3:0]. The delay, if selected, reduces input register hold time requirements when using a global clock.

The input block allows three modes of operation. In single data rate (SDR) the data is registered with the system clock by one of the registers in the single data rate sync register block.

In DDR mode, two registers are used to sample the data on the positive and negative edges of the modified DQS (ECLKDQSR) in the DDR Memory mode or ECLK signal when using DDR Generic mode, creating two data streams. Before entering the core, these two data streams are synchronized to the system clock to generate two data streams.

A gearbox function can be implemented in each of the input registers on the left and right sides. The gearbox function takes a double data rate signal applied to PIOA and converts it as four data streams, INA, IPA, INB and IPB. The two data streams from the first set of DDR registers are synchronized to the edge clock and then to the system clock before entering the core. Figure 2-30 provides further information on the use of the gearbox function.

The signal DDRCLKPOL controls the polarity of the clock used in the synchronization registers. It ensures adequate timing when data is transferred to the system clock domain from the ECLKDQSR (DDR Memory Interface mode) or ECLK (DDR Generic mode). The DDRLAT signal is used to ensure the data transfer from the synchronization registers to the clock transfer and gearbox registers.

The ECLKDQSR, DDRCLKPOL and DDRLAT signals are generated in the DQS Read Control Logic Block. See Figure 2-37 for an overview of the DQS read control logic.

Further discussion about using the DQS strobe in this module is discussed in the DDR Memory section of this data sheet.

Please see TN1180, LatticeECP3 High-Speed I/O Interface for more information on this topic.



### SCI (SERDES Client Interface) Bus

The SERDES Client Interface (SCI) is an IP interface that allows the SERDES/PCS Quad block to be controlled by registers rather than the configuration memory cells. It is a simple register configuration interface that allows SERDES/PCS configuration without power cycling the device.

The Diamond and ispLEVER design tools support all modes of the PCS. Most modes are dedicated to applications associated with a specific industry standard data protocol. Other more general purpose modes allow users to define their own operation. With these tools, the user can define the mode for each quad in a design.

Popular standards such as 10Gb Ethernet, x4 PCI Express and 4x Serial RapidIO can be implemented using IP (available through Lattice), a single quad (Four SERDES channels and PCS) and some additional logic from the core.

The LatticeECP3 family also supports a wide range of primary and secondary protocols. Within the same quad, the LatticeECP3 family can support mixed protocols with semi-independent clocking as long as the required clock frequencies are integer x1, x2, or x11 multiples of each other. Table 2-15 lists the allowable combination of primary and secondary protocol combinations.

# Flexible Quad SERDES Architecture

The LatticeECP3 family SERDES architecture is a quad-based architecture. For most SERDES settings and standards, the whole quad (consisting of four SERDES) is treated as a unit. This helps in silicon area savings, better utilization and overall lower cost.

However, for some specific standards, the LatticeECP3 quad architecture provides flexibility; more than one standard can be supported within the same quad.

Table 2-15 shows the standards can be mixed and matched within the same quad. In general, the SERDES standards whose nominal data rates are either the same or a defined subset of each other, can be supported within the same quad. In Table 2-15, the Primary Protocol column refers to the standard that determines the reference clock and PLL settings. The Secondary Protocol column shows the other standard that can be supported within the same quad.

Furthermore, Table 2-15 also implies that more than two standards in the same quad can be supported, as long as they conform to the data rate and reference clock requirements. For example, a quad may contain PCI Express 1.1, SGMII, Serial RapidIO Type I and Serial RapidIO Type II, all in the same quad.

### Table 2-15. LatticeECP3 Primary and Secondary Protocol Support

Primary Protocol	Secondary Protocol
PCI Express 1.1	SGMII
PCI Express 1.1	Gigabit Ethernet
PCI Express 1.1	Serial RapidIO Type I
PCI Express 1.1	Serial RapidIO Type II
Serial RapidIO Type I	SGMII
Serial RapidIO Type I	Gigabit Ethernet
Serial RapidIO Type II	SGMII
Serial RapidIO Type II	Gigabit Ethernet
Serial RapidIO Type II	Serial RapidIO Type I
CPRI-3	CPRI-2 and CPRI-1
3G-SDI	HD-SDI and SD-SDI



# Hot Socketing Specifications<sup>1, 2, 3</sup>

Symbol	Parameter	Condition	Min.	Тур.	Max.	Units
IDK_HS⁴	Input or I/O Leakage Current	$0 \le V_{IN} \le V_{IH}$ (Max.)		_	+/—1	mA
IDK <sup>5</sup> Input o	Input or I/O Leakage Current	$0 \le V_{IN} < V_{CCIO}$		_	+/—1	mA
	input of i/O Leakage Ourfeitt	$V_{CCIO} \le V_{IN} \le V_{CCIO} + 0.5V$	_	18		mA

1.  $V_{CC},\,V_{CCAUX}$  and  $V_{CCIO}$  should rise/fall monotonically.

2.  $I_{DK}$  is additive to  $I_{PU}$ ,  $I_{PD}$  or  $I_{BH}$ .

3. LVCMOS and LVTTL only.

4. Applicable to general purpose I/O pins located on the top and bottom sides of the device.

5. Applicable to general purpose I/O pins located on the left and right sides of the device.

# Hot Socketing Requirements<sup>1, 2</sup>

Description	Min.	Тур.	Max.	Units
Input current per SERDES I/O pin when device is powered down and inputs driven.	_	-	8	mA

1. Assumes the device is powered down, all supplies grounded, both P and N inputs driven by CML driver with maximum allowed VCCOB (1.575 V), 8b10b data, internal AC coupling.

2. Each P and N input must have less than the specified maximum input current. For a 16-channel device, the total input current would be 8 mA\*16 channels \*2 input pins per channel = 256 mA

# **ESD** Performance

Please refer to the LatticeECP3 Product Family Qualification Summary for complete qualification data, including ESD performance.



## LVPECL33

The LatticeECP3 devices support the differential LVPECL standard. This standard is emulated using complementary LVCMOS outputs in conjunction with a parallel resistor across the driver outputs. The LVPECL input standard is supported by the LVDS differential input buffer. The scheme shown in Figure 3-3 is one possible solution for point-to-point signals.

### Figure 3-3. Differential LVPECL33



### Table 3-3. LVPECL33 DC Conditions<sup>1</sup>

Parameter	Description	Typical	Units
V <sub>CCIO</sub>	Output Driver Supply (+/-5%)	3.30	V
Z <sub>OUT</sub>	Driver Impedance	10	Ω
R <sub>S</sub>	Driver Series Resistor (+/-1%)	93	Ω
R <sub>P</sub>	Driver Parallel Resistor (+/-1%)	196	Ω
R <sub>T</sub>	Receiver Termination (+/-1%)	100	Ω
V <sub>OH</sub>	Output High Voltage	2.05	V
V <sub>OL</sub>	Output Low Voltage	1.25	V
V <sub>OD</sub>	Output Differential Voltage	0.80	V
V <sub>CM</sub>	Output Common Mode Voltage	1.65	V
Z <sub>BACK</sub>	Back Impedance	100.5	Ω
I <sub>DC</sub>	DC Output Current	12.11	mA

### **Over Recommended Operating Conditions**

1. For input buffer, see LVDS table.



# LatticeECP3 External Switching Characteristics (Continued)<sup>1, 2, 3, 13</sup>

Parameter	Description	Device	Min.	Max.	Min.	Max.	Min.	Max.	Units
f <sub>MAX GDDR</sub>	DDRX1 Clock Frequency	ECP3-70EA/95EA	_	250	_	250		250	MHz
t <sub>DVBGDDR</sub>	Data Valid Before CLK	ECP3-35EA	683	_	688		690	_	ps
t <sub>DVAGDDR</sub>	Data Valid After CLK	ECP3-35EA	683	—	688	—	690	_	ps
f <sub>MAX GDDR</sub>	DDRX1 Clock Frequency	ECP3-35EA	—	250	—	250	_	250	MHz
t <sub>DVBGDDR</sub>	Data Valid Before CLK	ECP3-17EA	683	_	688		690		ps
t <sub>DVAGDDR</sub>	Data Valid After CLK	ECP3-17EA	683	—	688	—	690	_	ps
f <sub>MAX GDDR</sub>	DDRX1 Clock Frequency	ECP3-17EA	—	250	—	250	_	250	MHz
Generic DDRX1 Ou	tput with Clock and Data Aligne	d at Pin (GDDRX1_TX.	SCLK.Ali	gned) <sup>10</sup>					
t <sub>DIBGDDR</sub>	Data Invalid Before Clock	ECP3-150EA	—	335	—	338	—	341	ps
t <sub>DIAGDDR</sub>	Data Invalid After Clock	ECP3-150EA	—	335	—	338		341	ps
f <sub>MAX</sub> GDDR	DDRX1 Clock Frequency	ECP3-150EA	_	250	_	250		250	MHz
	Data Invalid Before Clock	ECP3-70EA/95EA	_	339	_	343		347	ps
t <sub>DIAGDDB</sub>	Data Invalid After Clock	ECP3-70EA/95EA	_	339	_	343		347	ps
f <sub>MAX</sub> GDDR	DDRX1 Clock Frequency	ECP3-70EA/95EA	_	250	_	250		250	MHz
	Data Invalid Before Clock	ECP3-35EA		322		320		321	ps
	Data Invalid After Clock	ECP3-35EA	_	322	_	320		321	ps
f <sub>MAX GDDB</sub>	DDRX1 Clock Frequency	ECP3-35EA	_	250	_	250		250	MHz
	Data Invalid Before Clock	ECP3-17EA		322		320		321	ps
	Data Invalid After Clock	ECP3-17EA	_	322	_	320		321	ps
f <sub>MAX GDDB</sub>	DDRX1 Clock Frequency	ECP3-17EA	_	250	_	250		250	MHz
Generic DDRX1 Output with Clock and Data (<10 Bits Wide) Centered at Pin (GDDRX1 TX.DQS.Centered) <sup>10</sup>									
Left and Right Side	25		-			-			
t <sub>DVBGDDR</sub>	Data Valid Before CLK	ECP3-150EA	670		670		670	_	ps
t <sub>DVAGDDR</sub>	Data Valid After CLK	ECP3-150EA	670	_	670	_	670	_	ps
f <sub>MAX GDDB</sub>	DDRX1 Clock Frequency	ECP3-150EA	_	250	_	250	_	250	MHz
	Data Valid Before CLK	ECP3-70EA/95EA	657		652		650	_	ps
t <sub>DVAGDDR</sub>	Data Valid After CLK	ECP3-70EA/95EA	657	_	652		650	_	ps
f <sub>MAX GDDB</sub>	DDRX1 Clock Frequency	ECP3-70EA/95EA	_	250	_	250	_	250	MHz
	Data Valid Before CLK	ECP3-35EA	670		675		676	_	ps
t <sub>DVAGDDR</sub>	Data Valid After CLK	ECP3-35EA	670	—	675	—	676	_	ps
f <sub>MAX GDDR</sub>	DDRX1 Clock Frequency	ECP3-35EA	—	250	—	250	_	250	MHz
t <sub>DVBGDDR</sub>	Data Valid Before CLK	ECP3-17EA	670	—	670	—	670	_	ps
t <sub>DVAGDDR</sub>	Data Valid After CLK	ECP3-17EA	670	_	670	_	670	_	ps
f <sub>MAX</sub> GDDR	DDRX1 Clock Frequency	ECP3-17EA	_	250	_	250		250	MHz
Generic DDRX2 Ou	tput with Clock and Data (>10 B	its Wide) Aligned at Pi	n (GDDR	X2_TX.A	ligned)				
Left and Right Side	es								
t <sub>DIBGDDR</sub>	Data Invalid Before Clock	All ECP3EA Devices	—	200	—	210	_	220	ps
t <sub>DIAGDDR</sub>	Data Invalid After Clock	All ECP3EA Devices	—	200	—	210	—	220	ps
f <sub>MAX GDDR</sub>	DDRX2 Clock Frequency	All ECP3EA Devices	_	500	_	420	_	375	MHz
Generic DDRX2 Ou	tput with Clock and Data (>10 B	its Wide) Centered at P	in Using	DQSDL	L (GDDF	X2_TX.C	QSDLL.	Centered	)11
Left and Right Side	S								
t <sub>DVBGDDR</sub>	Data Valid Before CLK	All ECP3EA Devices	400		400		431	_	ps
t <sub>DVAGDDR</sub>	Data Valid After CLK	All ECP3EA Devices	400	—	400	—	432	—	ps
f <sub>MAX_GDDR</sub>	DDRX2 Clock Frequency	All ECP3EA Devices	—	400	—	400	—	375	MHz

## **Over Recommended Commercial Operating Conditions**



# LatticeECP3 Internal Switching Characteristics<sup>1, 2, 5</sup>

		-8		-7		-6		
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Units.
PFU/PFF Logi	c Mode Timing							
t <sub>LUT4_PFU</sub>	LUT4 delay (A to D inputs to F output)	—	0.147	_	0.163	_	0.179	ns
t <sub>LUT6_PFU</sub>	LUT6 delay (A to D inputs to OFX output)	—	0.281		0.335	_	0.379	ns
t <sub>LSR_PFU</sub>	Set/Reset to output of PFU (Asynchronous)	—	0.593	—	0.674	—	0.756	ns
t <sub>LSRREC_PFU</sub>	Asynchronous Set/Reset recovery time for PFU Logic		0.298		0.345		0.391	ns
t <sub>SUM_PFU</sub>	Clock to Mux (M0,M1) Input Setup Time	0.134	_	0.144	_	0.153		ns
t <sub>HM_PFU</sub>	Clock to Mux (M0,M1) Input Hold Time	-0.097	_	-0.103	_	-0.109	_	ns
t <sub>SUD_PFU</sub>	Clock to D input setup time	0.061	_	0.068	_	0.075		ns
t <sub>HD_PFU</sub>	Clock to D input hold time	0.019	_	0.013	_	0.015		ns
t <sub>CK2Q_PFU</sub>	Clock to Q delay, (D-type Register Configuration)	_	0.243	_	0.273	_	0.303	ns
PFU Dual Port	Memory Mode Timing							
t <sub>CORAM_PFU</sub>	Clock to Output (F Port)	—	0.710	—	0.803	—	0.897	ns
t <sub>SUDATA_PFU</sub>	Data Setup Time	-0.137	_	-0.155	_	-0.174		ns
t <sub>HDATA_PFU</sub>	Data Hold Time	0.188	_	0.217	_	0.246	_	ns
t <sub>SUADDR_PFU</sub>	Address Setup Time	-0.227	_	-0.257	_	-0.286		ns
t <sub>HADDR_PFU</sub>	Address Hold Time	0.240	_	0.275	_	0.310	_	ns
t <sub>SUWREN_PFU</sub>	Write/Read Enable Setup Time	-0.055		-0.055	-	-0.063	_	ns
t <sub>HWREN_</sub> PFU	Write/Read Enable Hold Time	0.059	_	0.059	_	0.071	_	ns
PIC Timing								
PIO Input/Out	out Buffer Timing							
t <sub>IN_PIO</sub>	Input Buffer Delay (LVCMOS25)		0.423		0.466		0.508	ns
t <sub>OUT_PIO</sub>	Output Buffer Delay (LVCMOS25)	—	1.241	_	1.301	_	1.361	ns
IOLOGIC Inpu	t/Output Timing							
t <sub>SUI_PIO</sub>	Input Register Setup Time (Data Before Clock)	0.956		1.124		1.293		ns
t <sub>HI_PIO</sub>	Input Register Hold Time (Data after Clock)	0.225		0.184		0.240		ns
t <sub>COO_PIO</sub>	Output Register Clock to Output Delay <sup>4</sup>	-	1.09	-	1.16	-	1.23	ns
t <sub>SUCE_PIO</sub>	Input Register Clock Enable Setup Time	0.220	_	0.185	_	0.150	_	ns
t <sub>HCE_PIO</sub>	Input Register Clock Enable Hold Time	-0.085		-0.072		-0.058		ns
t <sub>SULSR_PIO</sub>	Set/Reset Setup Time	0.117	_	0.103	_	0.088	_	ns
t <sub>HLSR_PIO</sub>	Set/Reset Hold Time	-0.107	_	-0.094	_	-0.081	_	ns
EBR Timing								
t <sub>CO_EBR</sub>	Clock (Read) to output from Address or Data	—	2.78	—	2.89	—	2.99	ns
t <sub>COO_EBR</sub>	Clock (Write) to output from EBR output Register	—	0.31	—	0.32	—	0.33	ns
t <sub>SUDATA_EBR</sub>	Setup Data to EBR Memory	-0.218	_	-0.227	_	-0.237	_	ns
t <sub>HDATA_EBR</sub>	Hold Data to EBR Memory	0.249		0.257		0.265	—	ns
t <sub>SUADDR_EBR</sub>	Setup Address to EBR Memory	-0.071		-0.070		-0.068		ns
t <sub>HADDR_EBR</sub>	Hold Address to EBR Memory	0.118		0.098		0.077		ns
t <sub>SUWREN_EBR</sub>	Setup Write/Read Enable to EBR Memory	-0.107	_	-0.106	_	-0.106	—	ns

## **Over Recommended Commercial Operating Conditions**







Note: Input data and address are registered at the positive edge of the clock and output data appears after the positive edge of the clock.



# LatticeECP3 Maximum I/O Buffer Speed (Continued)<sup>1, 2, 3, 4, 5, 6</sup>

### **Over Recommended Operating Conditions**

Buffer	Buffer Description			
PCI33	PCI, V <sub>CCIO</sub> = 3.3 V	66	MHz	

1. These maximum speeds are characterized but not tested on every device.

2. Maximum I/O speed for differential output standards emulated with resistors depends on the layout.

3. LVCMOS timing is measured with the load specified in the Switching Test Conditions table of this document.

4. All speeds are measured at fast slew.

5. Actual system operation may vary depending on user logic implementation.

6. Maximum data rate equals 2 times the clock rate when utilizing DDR.



# **SERDES High Speed Data Receiver**

### Table 3-9. Serial Input Data Specifications

Symbol	Description		Min.	Тур.	Max.	Units
		3.125 G	—	—	136	
		2.5 G	—	—	144	
	Stream of nontransitions <sup>1</sup>	1.485 G	—	—	160	Dite
RX-OID <sub>S</sub>	(CID = Consecutive Identical Digits) @ 10 <sup>-12</sup> BER	622 M	—	—	204	DIIS
		270 M	—	—	228	
		150 M	—	—	296	
V <sub>RX-DIFF-S</sub>	Differential input sensitivity	150	—	1760	mV, p-p	
V <sub>RX-IN</sub>	Input levels		0	—	V <sub>CCA</sub> +0.5 <sup>4</sup>	V
V <sub>RX-CM-DC</sub>	Input common mode range (DC coupled)		0.6	—	V <sub>CCA</sub>	V
V <sub>RX-CM-AC</sub>	Input common mode range (AC coupled) <sup>3</sup>	0.1	—	V <sub>CCA</sub> +0.2	V	
T <sub>RX-RELOCK</sub>	SCDR re-lock time <sup>2</sup>	—	1000	—	Bits	
Z <sub>RX-TERM</sub>	Input termination 50/75 Ohm/High Z	-20%	50/75/HiZ	+20%	Ohms	
RL <sub>RX-RL</sub>	Return loss (without package)	10	—	—	dB	

1. This is the number of bits allowed without a transition on the incoming data stream when using DC coupling.

2. This is the typical number of bit times to re-lock to a new phase or frequency within +/- 300 ppm, assuming 8b10b encoded data.

3. AC coupling is used to interface to LVPECL and LVDS. LVDS interfaces are found in laser drivers and Fibre Channel equipment. LVDS interfaces are generally found in 622 Mbps SERDES devices.

4. Up to 1.76 V.

## Input Data Jitter Tolerance

A receiver's ability to tolerate incoming signal jitter is very dependent on jitter type. High speed serial interface standards have recognized the dependency on jitter type and have specifications to indicate tolerance levels for different jitter types as they relate to specific protocols. Sinusoidal jitter is considered to be a worst case jitter type.

Description	Frequency	Condition	Min.	Тур.	Max.	Units
Deterministic		600 mV differential eye	—	_	0.47	UI, p-p
Random	3.125 Gbps	600 mV differential eye	—	_	0.18	UI, p-p
Total		600 mV differential eye	—		0.65	UI, p-p
Deterministic		600 mV differential eye	—	_	0.47	UI, p-p
Random	2.5 Gbps	600 mV differential eye	—	_	0.18	UI, p-p
Total		600 mV differential eye			0.65	UI, p-p
Deterministic		600 mV differential eye	—	_	0.47	UI, p-p
Random	1.25 Gbps	600 mV differential eye	—	_	0.18	UI, p-p
Total		600 mV differential eye	—	_	0.65	UI, p-p
Deterministic		600 mV differential eye	—	_	0.47	UI, p-p
Random	622 Mbps	600 mV differential eye	—	_	0.18	UI, p-p
Total	]	600 mV differential eye	—	—	0.65	UI, p-p

Table 3-10. Receiver Total Jitter Tolerance Specification

Note: Values are measured with CJPAT, all channels operating, FPGA Logic active, I/Os around SERDES pins quiet, voltages are nominal, room temperature.



# Gigabit Ethernet/Serial Rapid I/O Type 1/SGMII/CPRI LV E.12 Electrical and Timing Characteristics

# AC and DC Characteristics

### Table 3-17. Transmit

Symbol	Description	Test Conditions	Min.	Тур.	Max.	Units
T <sub>RF</sub>	Differential rise/fall time	20%-80%	_	80		ps
Z <sub>TX_DIFF_DC</sub>	Differential impedance		80	100	120	Ohms
J <sub>TX_DDJ</sub> <sup>3, 4, 5</sup>	Output data deterministic jitter		_	—	0.10	UI
J <sub>TX_TJ</sub> <sup>2, 3, 4, 5</sup>	Total output data jitter			_	0.24	UI

1. Rise and fall times measured with board trace, connector and approximately 2.5 pf load.

2. Total jitter includes both deterministic jitter and random jitter. The random jitter is the total jitter minus the actual deterministic jitter.

3. Jitter values are measured with each CML output AC coupled into a 50-Ohm impedance (100-Ohm differential impedance).

4. Jitter and skew are specified between differential crossings of the 50% threshold of the reference signal.

5. Values are measured at 1.25 Gbps.

#### Table 3-18. Receive and Jitter Tolerance

Symbol	Description	Test Conditions	Min.	Тур.	Max.	Units
RL <sub>RX_DIFF</sub>	Differential return loss	From 100 MHz to 1.25 GHz	10			dB
RL <sub>RX_CM</sub>	Common mode return loss	From 100 MHz to 1.25 GHz	6			dB
Z <sub>RX_DIFF</sub>	Differential termination resistance		80	100	120	Ohms
J <sub>RX_DJ</sub> <sup>1, 2, 3, 4, 5</sup>	Deterministic jitter tolerance (peak-to-peak)		_	_	0.34	UI
J <sub>RX_RJ</sub> <sup>1, 2, 3, 4, 5</sup>	Random jitter tolerance (peak-to-peak)		-		0.26	UI
J <sub>RX_SJ</sub> <sup>1, 2, 3, 4, 5</sup>	Sinusoidal jitter tolerance (peak-to-peak)		-		0.11	UI
J <sub>RX_TJ</sub> <sup>1, 2, 3, 4, 5</sup>	Total jitter tolerance (peak-to-peak)		_	_	0.71	UI
T <sub>RX_EYE</sub>	Receiver eye opening		0.29	_	_	UI

1. Total jitter includes deterministic jitter, random jitter and sinusoidal jitter. The sinusoidal jitter tolerance mask is shown in Figure 3-18.

2. Jitter values are measured with each high-speed input AC coupled into a 50-Ohm impedance.

3. Jitter and skew are specified between differential crossings of the 50% threshold of the reference signal.

4. Jitter tolerance, Differential Input Sensitivity and Receiver Eye Opening parameters are characterized when Full Rx Equalization is enabled.

5. Values are measured at 1.25 Gbps.



# sysl/O Differential Electrical Characteristics

# Transition Reduced LVDS (TRLVDS DC Specification)

### **Over Recommended Operating Conditions**

Symbol	Description	Min.	Nom.	Max.	Units
V <sub>CCO</sub>	Driver supply voltage (+/- 5%)	3.14	3.3	3.47	V
V <sub>ID</sub>	Input differential voltage	150	_	1200	mV
V <sub>ICM</sub>	Input common mode voltage	3	_	3.265	V
V <sub>CCO</sub>	Termination supply voltage	3.14	3.3	3.47	V
R <sub>T</sub>	Termination resistance (off-chip)	45	50	55	Ohms

Note: LatticeECP3 only supports the TRLVDS receiver.



### Mini LVDS

### **Over Recommended Operating Conditions**

Parameter Symbol	Description	Min.	Тур.	Max.	Units
Z <sub>O</sub>	Single-ended PCB trace impedance	30	50	75	Ohms
R <sub>T</sub>	Differential termination resistance	50	100	150	Ohms
V <sub>OD</sub>	Output voltage, differential,  V <sub>OP</sub> - V <sub>OM</sub>	300	_	600	mV
V <sub>OS</sub>	Output voltage, common mode, $ V_{OP} + V_{OM} /2$	1	1.2	1.4	V
$\Delta V_{OD}$	Change in V <sub>OD</sub> , between H and L	—	_	50	mV
$\Delta V_{ID}$	Change in V <sub>OS</sub> , between H and L	—	_	50	mV
V <sub>THD</sub>	Input voltage, differential,  V <sub>INP</sub> - V <sub>INM</sub>	200	_	600	mV
V <sub>CM</sub>	Input voltage, common mode, $ V_{INP} + V_{INM} /2$	0.3+(V <sub>THD</sub> /2)	_	2.1-(V <sub>THD</sub> /2)	
T <sub>R</sub> , T <sub>F</sub>	Output rise and fall times, 20% to 80%	—	_	550	ps
T <sub>ODUTY</sub>	Output clock duty cycle	40	—	60	%

Note: Data is for 6 mA differential current drive. Other differential driver current options are available.



# Pin Information Summary (Cont.)

Pin Information Sun	nmary		ECP3-17EA		ECP3-35EA			
Pin Type		256 ftBGA	328 csBGA	484 fpBGA	256 ftBGA	484 fpBGA	672 fpBGA	
	Bank 0	13	10	18	13	21	24	
	Bank 1	7	5	12	7	18	18	
	Bank 2	2	2	4	1	8	8	
Emulated Differential I/O per	Bank 3	4	2	13	5	20	19	
Dank	Bank 6	5	1	13	6	22	20	
	Bank 7	6	9	10	6	11	13	
	Bank 8	12	12	12	12	12	12	
	Bank 0	0	0	0	0	0	0	
	Bank 1	0	0	0	0	0	0	
	Bank 2	2	2	3	3	6	6	
Highspeed Differential I/O per	Bank 3	5	4	9	4	9	12	
bank	Bank 6	5	4	9	4	11	12	
	Bank 7	5	6	8	5	9	10	
	Bank 8	0	0	0	0	0	0	
	Bank 0	26/13	20/10	36/18	26/13	42/21	48/24	
	Bank 1	14/7	10/5	24/12	14/7	36/18	36/18	
	Bank 2	8/4	9/4	14/7	8/4	28/14	28/14	
Differential I/O per Bank	Bank 3	18/9	12/6	44/22	18/9	58/29	63/31	
	Bank 6	20/10	11/5	44/22	20/10	67/33	65/32	
	Bank 7	23/11	30/15	36/18	23/11	40/20	46/23	
	Bank 8	24/12	24/12	24/12	24/12	24/12	24/12	
	Bank 0	2	1	3	2	3	4	
	Bank 1	1	0	2	1	3	3	
	Bank 2	0	0	1	0	2	2	
DDR Groups Bonded per	Bank 3	1	0	3	1	3	4	
Bank <sup>2</sup>	Bank 6	1	0	3	1	4	4	
	Bank 7	1	2	2	1	3	3	
	Configuration Bank 8	0	0	0	0	0	0	
SERDES Quads		1	1	1	1	1	1	

These pins must remain floating on the board.
Some DQS groups may not support DQS-12. Refer to the device pinout (.csv) file.



# Package Pinout Information

Package pinout information can be found under "Data Sheets" on the LatticeECP3 product pages on the Lattice website at http://www.latticesemi.com/Products/FPGAandCPLD/LatticeECP3 and in the Diamond or ispLEVER software tools. To create pinout information from within ispLEVER Design Planner, select **Tools > Spreadsheet View**. Then select **Select File > Export** and choose a type of output file. To create a pin information file from within Diamond select **Tools > Spreadsheet View** or **Tools >Package View**; then, select **File > Export** and choose a type of output file. See Diamond or ispLEVER Help for more information.

# **Thermal Management**

Thermal management is recommended as part of any sound FPGA design methodology. To assess the thermal characteristics of a system, Lattice specifies a maximum allowable junction temperature in all device data sheets. Designers must complete a thermal analysis of their specific design to ensure that the device and package do not exceed the junction temperature limits. Refer to the Thermal Management document to find the device/package specific thermal values.

# For Further Information

For further information regarding Thermal Management, refer to the following:

- Thermal Management document
- TN1181, Power Consumption and Management for LatticeECP3 Devices
- Power Calculator tool included with the Diamond and ispLEVER design tools, or as a standalone download from www.latticesemi.com/software



Part Number	Voltage	Grade <sup>1</sup>	Power	Package	Pins	Temp.	LUTs (K)
LFE3-70EA-6FN484C	1.2 V	-6	STD	Lead-Free fpBGA	484	COM	67
LFE3-70EA-7FN484C	1.2 V	-7	STD	Lead-Free fpBGA	484	COM	67
LFE3-70EA-8FN484C	1.2 V	-8	STD	Lead-Free fpBGA	484	COM	67
LFE3-70EA-6LFN484C	1.2 V	-6	LOW	Lead-Free fpBGA	484	COM	67
LFE3-70EA-7LFN484C	1.2 V	-7	LOW	Lead-Free fpBGA	484	COM	67
LFE3-70EA-8LFN484C	1.2 V	-8	LOW	Lead-Free fpBGA	484	COM	67
LFE3-70EA-6FN672C	1.2 V	-6	STD	Lead-Free fpBGA	672	COM	67
LFE3-70EA-7FN672C	1.2 V	-7	STD	Lead-Free fpBGA	672	COM	67
LFE3-70EA-8FN672C	1.2 V	-8	STD	Lead-Free fpBGA	672	COM	67
LFE3-70EA-6LFN672C	1.2 V	-6	LOW	Lead-Free fpBGA	672	COM	67
LFE3-70EA-7LFN672C	1.2 V	-7	LOW	Lead-Free fpBGA	672	COM	67
LFE3-70EA-8LFN672C	1.2 V	-8	LOW	Lead-Free fpBGA	672	COM	67
LFE3-70EA-6FN1156C	1.2 V	-6	STD	Lead-Free fpBGA	1156	COM	67
LFE3-70EA-7FN1156C	1.2 V	-7	STD	Lead-Free fpBGA	1156	COM	67
LFE3-70EA-8FN1156C	1.2 V	-8	STD	Lead-Free fpBGA	1156	COM	67
LFE3-70EA-6LFN1156C	1.2 V	-6	LOW	Lead-Free fpBGA	1156	COM	67
LFE3-70EA-7LFN1156C	1.2 V	-7	LOW	Lead-Free fpBGA	1156	COM	67
LFE3-70EA-8LFN1156C	1.2 V	-8	LOW	Lead-Free fpBGA	1156	COM	67

1. For ordering information on -9 speed grade devices, please contact your Lattice Sales Representative.

Part Number	Voltage	Grade <sup>1</sup>	Power	Package	Pins	Temp.	LUTs (K)
LFE3-95EA-6FN484C	1.2 V	-6	STD	Lead-Free fpBGA	484	COM	92
LFE3-95EA-7FN484C	1.2 V	-7	STD	Lead-Free fpBGA	484	COM	92
LFE3-95EA-8FN484C	1.2 V	-8	STD	Lead-Free fpBGA	484	COM	92
LFE3-95EA-6LFN484C	1.2 V	-6	LOW	Lead-Free fpBGA	484	COM	92
LFE3-95EA-7LFN484C	1.2 V	-7	LOW	Lead-Free fpBGA	484	COM	92
LFE3-95EA-8LFN484C	1.2 V	-8	LOW	Lead-Free fpBGA	484	COM	92
LFE3-95EA-6FN672C	1.2 V	-6	STD	Lead-Free fpBGA	672	COM	92
LFE3-95EA-7FN672C	1.2 V	-7	STD	Lead-Free fpBGA	672	COM	92
LFE3-95EA-8FN672C	1.2 V	-8	STD	Lead-Free fpBGA	672	COM	92
LFE3-95EA-6LFN672C	1.2 V	-6	LOW	Lead-Free fpBGA	672	COM	92
LFE3-95EA-7LFN672C	1.2 V	-7	LOW	Lead-Free fpBGA	672	COM	92
LFE3-95EA-8LFN672C	1.2 V	-8	LOW	Lead-Free fpBGA	672	COM	92
LFE3-95EA-6FN1156C	1.2 V	-6	STD	Lead-Free fpBGA	1156	COM	92
LFE3-95EA-7FN1156C	1.2 V	-7	STD	Lead-Free fpBGA	1156	COM	92
LFE3-95EA-8FN1156C	1.2 V	-8	STD	Lead-Free fpBGA	1156	COM	92
LFE3-95EA-6LFN1156C	1.2 V	-6	LOW	Lead-Free fpBGA	1156	COM	92
LFE3-95EA-7LFN1156C	1.2 V	-7	LOW	Lead-Free fpBGA	1156	COM	92
LFE3-95EA-8LFN1156C	1.2 V	-8	LOW	Lead-Free fpBGA	1156	COM	92

1. For ordering information on -9 speed grade devices, please contact your Lattice Sales Representative.



### Industrial

The following devices may have associated errata. Specific devices with associated errata will be notated with a footnote.

Part Number	Voltage	Grade	Power	Package <sup>1</sup>	Pins	Temp.	LUTs (K)
LFE3-17EA-6FTN256I	1.2 V	-6	STD	Lead-Free ftBGA	256	IND	17
LFE3-17EA-7FTN256I	1.2 V	-7	STD	Lead-Free ftBGA	256	IND	17
LFE3-17EA-8FTN256I	1.2 V	-8	STD	Lead-Free ftBGA	256	IND	17
LFE3-17EA-6LFTN256I	1.2 V	-6	LOW	Lead-Free ftBGA	256	IND	17
LFE3-17EA-7LFTN256I	1.2 V	-7	LOW	Lead-Free ftBGA	256	IND	17
LFE3-17EA-8LFTN256I	1.2 V	-8	LOW	Lead-Free ftBGA	256	IND	17
LFE3-17EA-6MG328I	1.2 V	-6	STD	Lead-Free csBGA	328	IND	17
LFE3-17EA-7MG328I	1.2 V	-7	STD	Lead-Free csBGA	328	IND	17
LFE3-17EA-8MG328I	1.2 V	-8	STD	Lead-Free csBGA	328	IND	17
LFE3-17EA-6LMG328I	1.2 V	-6	LOW	Green csBGA	328	IND	17
LFE3-17EA-7LMG328I	1.2 V	-7	LOW	Green csBGA	328	IND	17
LFE3-17EA-8LMG328I	1.2 V	-8	LOW	Green csBGA	328	IND	17
LFE3-17EA-6FN484I	1.2 V	-6	STD	Lead-Free fpBGA	484	IND	17
LFE3-17EA-7FN484I	1.2 V	-7	STD	Lead-Free fpBGA	484	IND	17
LFE3-17EA-8FN484I	1.2 V	-8	STD	Lead-Free fpBGA	484	IND	17
LFE3-17EA-6LFN484I	1.2 V	-6	LOW	Lead-Free fpBGA	484	IND	17
LFE3-17EA-7LFN484I	1.2 V	-7	LOW	Lead-Free fpBGA	484	IND	17
LFE3-17EA-8LFN484I	1.2 V	-8	LOW	Lead-Free fpBGA	484	IND	17

1. Green = Halogen free and lead free.

Part Number	Voltage	Grade <sup>1</sup>	Power	Package	Pins	Temp.	LUTs (K)
LFE3-35EA-6FTN256I	1.2 V	-6	STD	Lead-Free ftBGA	256	IND	33
LFE3-35EA-7FTN256I	1.2 V	-7	STD	Lead-Free ftBGA	256	IND	33
LFE3-35EA-8FTN256I	1.2 V	-8	STD	Lead-Free ftBGA	256	IND	33
LFE3-35EA-6LFTN256I	1.2 V	-6	LOW	Lead-Free ftBGA	256	IND	33
LFE3-35EA-7LFTN256I	1.2 V	-7	LOW	Lead-Free ftBGA	256	IND	33
LFE3-35EA-8LFTN256I	1.2 V	-8	LOW	Lead-Free ftBGA	256	IND	33
LFE3-35EA-6FN484I	1.2 V	-6	STD	Lead-Free fpBGA	484	IND	33
LFE3-35EA-7FN484I	1.2 V	-7	STD	Lead-Free fpBGA	484	IND	33
LFE3-35EA-8FN484I	1.2 V	-8	STD	Lead-Free fpBGA	484	IND	33
LFE3-35EA-6LFN484I	1.2 V	-6	LOW	Lead-Free fpBGA	484	IND	33
LFE3-35EA-7LFN484I	1.2 V	-7	LOW	Lead-Free fpBGA	484	IND	33
LFE3-35EA-8LFN484I	1.2 V	-8	LOW	Lead-Free fpBGA	484	IND	33
LFE3-35EA-6FN672I	1.2 V	-6	STD	Lead-Free fpBGA	672	IND	33
LFE3-35EA-7FN672I	1.2 V	-7	STD	Lead-Free fpBGA	672	IND	33
LFE3-35EA-8FN672I	1.2 V	-8	STD	Lead-Free fpBGA	672	IND	33
LFE3-35EA-6LFN672I	1.2 V	-6	LOW	Lead-Free fpBGA	672	IND	33
LFE3-35EA-7LFN672I	1.2 V	-7	LOW	Lead-Free fpBGA	672	IND	33
LFE3-35EA-8LFN672I	1.2 V	-8	LOW	Lead-Free fpBGA	672	IND	33

1. For ordering information on -9 speed grade devices, please contact your Lattice Sales Representative.



Date	Version	Section	Change Summary
			Updated Simplified Channel Block Diagram for SERDES/PCS Block diagram.
			Updated Device Configuration text section.
			Corrected software default value of MCCLK to be 2.5 MHz.
		DC and Switching Characteristics	Updated VCCOB Min/Max data in Recommended Operating Conditions table.
			Corrected footnote 2 in sysIO Recommended Operating Conditions table.
			Added added footnote 7 for t <sub>SKEW_PRIB</sub> to External Switching Characteristics table.
			Added 2-to-1 Gearing text section and table.
			Updated External Reference Clock Specification (refclkp/refclkn) table.
			LatticeECP3 sysCONFIG Port Timing Specifications - updated t <sub>DINIT</sub> information.
			Added sysCONFIG Port Timing waveform.
			Serial Input Data Specifications table, delete Typ data for $V_{RX-DIFF-S}$ .
			Added footnote 4 to sysCLOCK PLL Timing table for t <sub>PFD</sub> .
			Added SERDES/PCS Block Latency Breakdown table.
			External Reference Clock Specifications table, added footnote 4, add symbol name vREF-IN-DIFF.
			Added SERDES External Reference Clock Waveforms.
			Updated Serial Output Timing and Levels table.
			Pin-to-pin performance table, changed "typically 3% slower" to "typically slower".
			Updated timing information
			Updated SERDES minimum frequency.
			Added data to the following tables: External Switching Characteristics, Internal Switching Characteristics, Family Timing Adders, Maximum I/O Buffer Speed, DLL Timing, High Speed Data Transmitter, Channel Out- put Jitter, Typical Building Block Function Performance, Register-to- Register Performance, and Power Supply Requirements.
			Updated Serial Input Data Specifications table.
			Updated Transmit table, Serial Rapid I/O Type 2 Electrical and Timing Characteristics section.
		Pinout Information	Updated Signal Description tables.
			Updated Pin Information Summary tables and added footnote 1.
February 2009	01.0	_	Initial release.